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Semiconductor devices

Part 18-3: Semiconductor bio sensors — Fluid flow characteristics of lens-free CMOS photonic array sensor package modules with fluidic system

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FDIS	Report on voting
47E/682/FDIS	47E/690/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

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INTRODUCTION

The IEC 60747-18 series on semiconductor bio sensors is composed of the following parts:

- IEC 60747-18-1 defines the test method and data analysis for calibration of lens-free CMOS photonic array sensors
- IEC 60747-18-2 defines the evaluation process of lens-free CMOS photonic array sensor package modules
- IEC 60747-18-3 defines the fluid flow characteristics of lens-free CMOS photonic array sensor package modules with fluidic system

The IEC 60747-18 series includes subjects such as noise analysis, long-term reliability tests, test methods for lens-free CMOS photonic array sensor package modules under patchable environments, test methods under implantable environments, etc.

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PCT/KR2017/011031	[SOL]	METHOD FOR EVALUATING FLUID FLOW CHARACTERISTICS OF LENS-FREE CMOS OPTICAL ARRAY SENSOR PACKAGE MODULE HAVING FLOW CHANNEL	Subclause 4.4 Clause 5, 6
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